

# Consumer SSD E1000 Series

### Introduction

Consumer SSD E1000 adopts M.2 interface, advanced SSD control computing chip and 3D NAND flash to effectively improve R/W speed and ensure datasecurity.



It applies to personal computer and small-size proxy server to providing stable and high-speed service. It can also improve the high-end gaming experience and 3D graphics editing performance.

### **Available Models**

HS-SSD-E1000 128GB

HS-SSD-E1000 256GB

HS-SSD-E1000 512GB

HS-SSD-E1000 1024GB

## **Typical Application**

- PC (notebook and desktop)
- Small-size proxy sever

#### **Features and Functions**

- High R/W Speed Supports
  Max. read speed up to 2500 MB/s
- 3D NAND

Adopts 3D NAND flash to optimize capacity, performance and stability

Shockproof

No mechanical structure Adopts electronic chips control High data security

M.2 Interface





# **Specifications**

Model		HS-SSD-E1000			
Capacity		128GB	256GB	512GB	1024GB
Form Factor		M.2(2280)			
Interface		PCIe Gen3×4			
Max. sequential 128 K read speed		980 MB/s	2300 MB/s	2500 MB/s	2500 MB/s
Max. sequential 128 K write speed		620 MB/s	1200 MB/s	2100 MB/s	2100 MB/s
Max. random 4 K read IOPS		40 K	200 K	295 K	295 K
Max. random 4 K write IOPS		134 K	250 K	430 K	430 K
Power	Read (RMS max.)	3 W	3 W	3 W	3 W
consumption	Write (RMS max.)	2.9 W	2.9 W	3.5 W	3.5 W
Endurance (TBW) 4		80 TB	160 TB	320 TB	640 TB
NAND flash memory		3D TLC			
Weight		≤ 8 g			
MTBF (Mean Time between Failures) 5		1,500,000 h			
Operation temperature		0 °C to 70 °C (32 °F to 158 °F)			
Operation humidity		5% to 95% (no condensation)			
Limited warranty period		3 years			

<sup>\*:</sup> Performance test is performed in a specific testing environment. Any change of computer system, operation system, hardware, software, or functions will influence the test result.

- 1 2: Performance in the specifications is tested based on CrystalDiskMark.
- 3: Power consumption may differ according to flash configuration and platform. Power consumptions are measured by using CrystalDiskMark 1000 MB to test sequential R/W 5 times. Power consumptions are measured when sequential Read [1/5] to [5/5] and sequential Write [1/5] to [5/5].
- 4: The TBW value is calculated based on Workload of JEDC 218B/219Astandard.
- **5**: The MTBF value is calculated based on the functional failure rate of JEDC 218B/219A standard.

